

<b>Notice of References Cited</b>	Application/Control No. 10/726,768	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,706,592	03-2004	Chern et al.	438/257
*	B	US-2004/0084713	05-2004	Hsieh, Chia-Ta	257/315
	C	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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